

<b>Notice of References Cited</b>	Application/Control No. 10/530,677	Applicant(s)/Patent Under Reexamination YOSHINO ET AL.	
	Examiner Anca Eoff	Art Unit 1795	Page 1 of 1

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*	B	US-2004/0009428	01-2004	Tamura et al.	430/280.1
*	C	US-6,784,221	08-2004	Roth et al.	522/51
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	N	WO 03/005126	01-2003		Tamura, K. et al.	
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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